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ON Semiconductor®

### **FQD3P50TM-F085**

### **500V P-Channel MOSFET**

### **General Description**

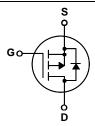
These P-Channel enhancement mode power field effect transistors are produced using ON Semiconductor's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for electronic lamp ballast based on complimentary half bridge.

#### **Features**

- -2.1A, -500V,  $R_{DS(on)}$  = 4.9 $\Omega$  @V<sub>GS</sub> = -10 V
- Low gate charge (typical 18 nC)
- Low Crss (typical 9.5 pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability
- Qualified to AEC Q101
- **RoHS Compliant**





### Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter		FQD3P50TM-F085	Units
V <sub>DSS</sub>	Drain-Source Voltage		-500	V
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°	C)	-2.1	Α
	- Continuous (T <sub>C</sub> = 100	°C)	-1.33	Α
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	-8.4	А
V <sub>GSS</sub>	Gate-Source Voltage		± 30	V
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	250	mJ
I <sub>AR</sub>	Avalanche Current	(Note 1)	-2.1	А
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	5.0	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	-4.5	V/ns
P <sub>D</sub>	Power Dissipation (T <sub>A</sub> = 25°C) *		2.5	W
	Power Dissipation (T <sub>C</sub> = 25°C)		50	W
	- Derate above 25°C		0.4	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C
T <sub>L</sub>	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

### **Thermal Characteristics**

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		2.5	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *		50	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		110	°C/W

<sup>\*</sup> When mounted on the minimum pad size recommended (PCB Mount)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	racteristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0 V, I <sub>D</sub> = -250 μA	-500			V
ΔBV <sub>DSS</sub> / ΔΤ <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = -250 μA, Referenced to 25°C		0.42		V/°C
I <sub>DSS</sub>	Zana Oata Valtana Darin Oamari	V <sub>DS</sub> = -500 V, V <sub>GS</sub> = 0 V			-1	μА
	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -400 V, T <sub>C</sub> = 125°C			-10	μА
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = -30 V, V <sub>DS</sub> = 0 V			-100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = 30 V, V <sub>DS</sub> = 0 V		-	100	nA
On Cha	racteristics					
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250 μA	-3.0		-5.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = -10 V, I <sub>D</sub> = -1.05 A		3.9	4.9	Ω
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = -50 V, I <sub>D</sub> = -1.05 A (Note 4)		2.1		S
C <sub>iss</sub>	Input Capacitance Output Capacitance	$V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		510 70	660 90	pF pF
C <sub>rss</sub>	Reverse Transfer Capacitance			9.5	12	pF
Switchi	ng Characteristics					
t <sub>d(on)</sub>	Turn-On Delay Time	V = 250 V L = 2.7 A		12	35	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = -250 \text{ V}, I_{D} = -2.7 \text{ A},$ $R_{G} = 25 \Omega$		56	120	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	NG - 23 22		35	80	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4, 5)		45	100	ns
Qg	Total Gate Charge	V <sub>DS</sub> = -400 V, I <sub>D</sub> = -2.7 A,		18	23	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = -10 V		3.6		nC
Q <sub>gd</sub>	Gate-Drain Charge	(Note 4, 5)		9.2		nC
Drain-S	ource Diode Characteristics a	nd Maximum Ratings				
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current				-2.1	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode F	orward Current		-	-8.4	Α
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = -2.1 A			-5.0	V
t <sub>rr</sub>	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = -2.7 \text{ A},$		270		ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)		1.5		μС

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 102mH, I<sub>AS</sub> = -2.1A, V<sub>DD</sub> = -50V, R<sub>G</sub> = 25  $\Omega$ , Starting T<sub>J</sub> = 25°C 3. I<sub>SD</sub>  $\leq$  -2.7A, dil/dt  $\leq$  200A/μs, V<sub>DD</sub>  $\leq$  BV<sub>DSS</sub>, Starting T<sub>J</sub> = 25°C 4. Pulse Test : Pulse width  $\leq$  300μs, Duty cycle  $\leq$  2% 5. Essentially independent of operating temperature

## **Typical Characteristics**

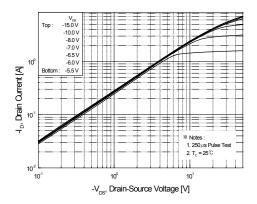


Figure 1. On-Region Characteristics

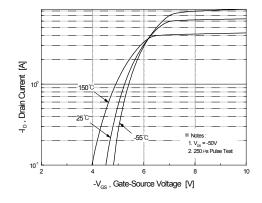


Figure 2. Transfer Characteristics

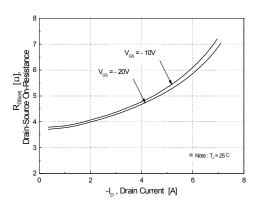


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

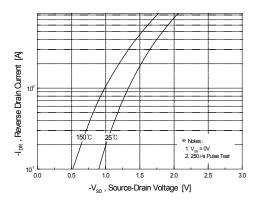


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

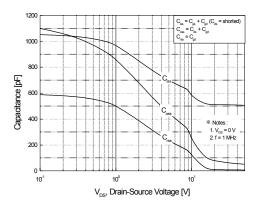


Figure 5. Capacitance Characteristics

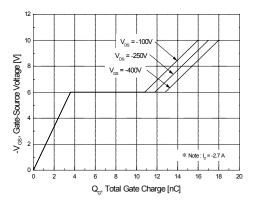


Figure 6. Gate Charge Characteristics



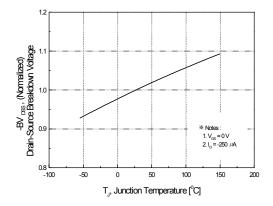
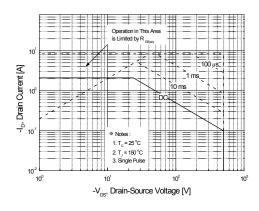


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



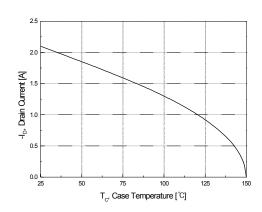


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

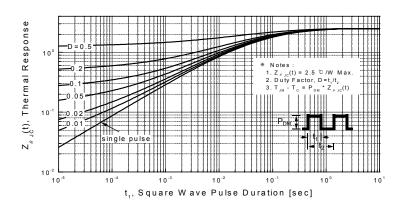
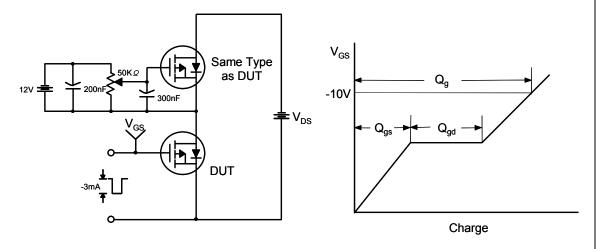
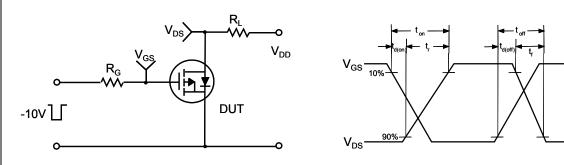


Figure 11. Transient Thermal Response Curve

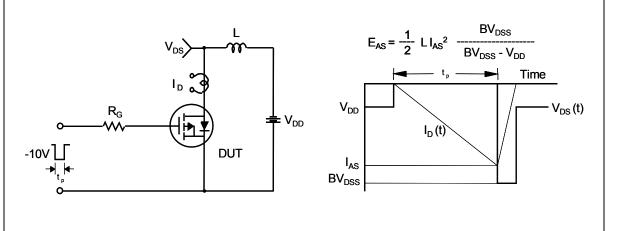
### **Gate Charge Test Circuit & Waveform**



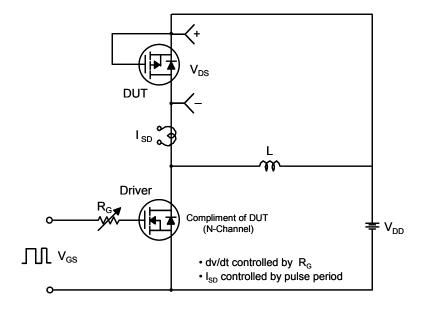
### **Resistive Switching Test Circuit & Waveforms**

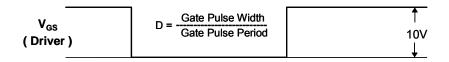


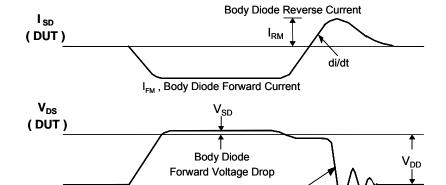
### **Unclamped Inductive Switching Test Circuit & Waveforms**



### Peak Diode Recovery dv/dt Test Circuit & Waveforms





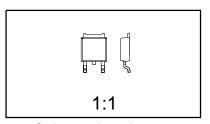


Body Diode Recovery dv/dt

### **Mechanical Dimensions**

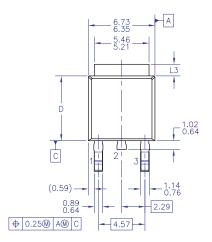
# TO-252 (DPAK) (FS PKG Code 36)

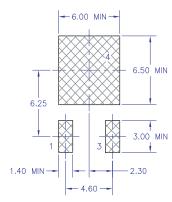




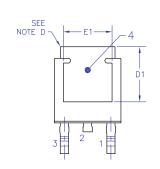
Scale 1:1 on letter size paper Dimensions shown below are in: millimeters

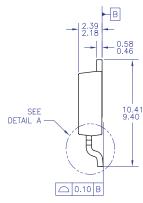
Part Weight per unit (gram): 0.33

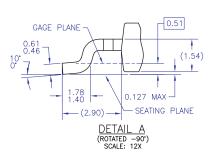




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- NOTES: UNLESS OTHERWISE SPECIFIED

  - ALL DIMENSIONS ARE IN MILLIMETERS.
    THIS PACKAGE CONFORMS TO JEDEC, TO-252,
    ISSUE C, VARIATION AA & AB, DATED NOV. 1999.

  - DIMENSIONING AND TOLERANCING PER
    ASME Y14.5M-1994.
    HEAT SINK TOP EDGE COULD BE IN CHAMFERED
    CORNERS OR EDGE PROTRUSION.
    DIMENSIONS L3D,PE18D1 TABLE:

	OPTION AA	OPTION AB
L3	0.89-1.27	1.52-2.03
D	5.97-6.22	5.33-5.59
E1	4.32 MIN	3.81 MIN
D1	5.21 MIN	4.57 MIN

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